Most Frequently Occurring Classifications of Patents Returned
From A Search of 09872582 on May 19, 2004

Original Classifications
```
10   365/201
 7   714/733
 4   714/30
 4   714/718
 3   365/200
 3   714/7
 3   714/726
 2   714/719
 2   714/720
 2   714/724
 2   714/732
```

Cross-Reference Classifications
```
16   714/733
10   365/201
10   714/718
 5   365/200
 4   714/710
 4   714/732
 3   365/236
 3   714/30
 3   714/42
 3   714/711
 3   714/726
 3   714/734
 3   714/736
 3   714/738
 2   365/230.03
 2   714/6
 2   714/719
 2   714/725
 2   714/729
 2   714/742
 2   714/8
```

Combined Classifications
```
23   714/733
20   365/201
14   714/718
 8   365/200
 7   714/30
 6   714/726
 6   714/732
```

5   714/710
4   714/42
4   714/7
4   714/711
4   714/719
3   365/236
3   714/720
3   714/734
3   714/736
3   714/738
2   365/230.03
2   714/6
2   714/724
2   714/725
2   714/729
2   714/742
2   714/8

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09872582 on May 19, 2004


```
 23  714/733        (7 OR, 16 XR)
            Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                             DETECTION/RECOVERY
         714/699          PULSE OR DATA ERROR HANDLING
         714/724          .Digital logic testing
         714/733          ..Built-in testing circuit (BILBO)


 20  365/201        (10 OR, 10 XR)
            Class   365 :  STATIC INFORMATION STORAGE AND RETRIEVAL
         365/189.01      READ/WRITE CIRCUIT
         365/201          .Testing


 14  714/718        (4 OR, 10 XR)
            Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                             DETECTION/RECOVERY
         714/699          PULSE OR DATA ERROR HANDLING
         714/718          .Memory testing


  8  365/200        (3 OR, 5 XR)
            Class   365 :  STATIC INFORMATION STORAGE AND RETRIEVAL
         365/189.01      READ/WRITE CIRCUIT
         365/200          .Bad bit


  7  714/30         (4 OR, 3 XR)
            Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                             DETECTION/RECOVERY
         714/100          DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

         714/1            .Reliability and availability
         714/25           ..Fault locating (i.e., diagnosis or testing)

         714/27           ...Particular access structure
         714/30           ....Built-in hardware for diagnosing or testing
                             within-system component (e.g., microprocessor test mode
                             circuit, scan path)


  6  714/726        (3 OR, 3 XR)
            Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                             DETECTION/RECOVERY
         714/699          PULSE OR DATA ERROR HANDLING
         714/724          .Digital logic testing
```

```
          714/726        ..Scan path testing (e.g., level sensitive sca
n
                           design (LSSD))


   6  714/732        (2 OR,  4 XR)
          Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                           DETECTION/RECOVERY
          714/699         PULSE OR DATA ERROR HANDLING
          714/724         .Digital logic testing
          714/732         ..Signature analysis


   5  714/710        (1 OR,  4 XR)
          Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                           DETECTION/RECOVERY
          714/699         PULSE OR DATA ERROR HANDLING
          714/710         .Replacement of memory spare location, portion
 ,
                           or segment


   4  714/42         (1 OR,  3 XR)
          Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                           DETECTION/RECOVERY
          714/100         DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

          714/1           .Reliability and availability
          714/25          ..Fault locating (i.e., diagnosis or testing)

          714/40          ...Component dependent technique
          714/42          ....Memory or storage device component fault


   4  714/7          (3 OR,  1 XR)
          Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                           DETECTION/RECOVERY
          714/100         DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

          714/1           .Reliability and availability
          714/2           ..Fault recovery
          714/3           ...By masking or reconfiguration
          714/5           ....Of memory or peripheral subsystem
          714/6           .....Redundant stored data accessed (e.g.,
                             duplicated data, error correction coded da
ta, or other
                           parity-type data)
          714/7           ......Reconfiguration (e.g., adding a
                           replacement storage component)


   4  714/711        (1 OR,  3 XR)
          Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
```

```
                    09872582_CLSTITLES
                    DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/710        .Replacement of memory spare location, portion

                          or segment
        714/711        ..Spare row or column


  4   714/719      (2 OR, 2 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/718        .Memory testing
        714/719        ..Read-in with read-out and compare


  3   365/236      (0 OR, 3 XR)
        Class    365 :   STATIC INFORMATION STORAGE AND RETRIEVAL
        365/230.01     ADDRESSING
        365/236        .Counting


  3   714/720      (2 OR, 1 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/718        .Memory testing
        714/719        ..Read-in with read-out and compare
        714/720        ...Special test pattern (e.g., checkerboard,
                          walking ones)


  3   714/734      (0 OR, 3 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/724        .Digital logic testing
        714/734        ..Structural (in-circuit test)


  3   714/736      (0 OR, 3 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/724        .Digital logic testing
        714/736        ..Device response compared to expected
                          fault-free response


  3   714/738      (0 OR, 3 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/724        .Digital logic testing
```

```
              714/738         ..Including test pattern generator


  2   365/230.03     (0 OR, 2 XR)
              Class    365 :   STATIC INFORMATION STORAGE AND RETRIEVAL
              365/230.01     ADDRESSING
              365/230.03     .Plural blocks or banks


  2   714/6          (0 OR, 2 XR)
              Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                                  DETECTION/RECOVERY
              714/100          DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

              714/1            .Reliability and availability
              714/2            ..Fault recovery
              714/3            ...By masking or reconfiguration
              714/5            ....Of memory or peripheral subsystem
              714/6            .....Redundant stored data accessed (e.g.,
                                  duplicated data, error correction coded dat
a, or other

                               parity-type data)


  2   714/724         (2 OR, 0 XR)
              Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                                  DETECTION/RECOVERY
              714/699          PULSE OR DATA ERROR HANDLING
              714/724          .Digital logic testing


  2   714/725         (0 OR, 2 XR)
              Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                                  DETECTION/RECOVERY
              714/699          PULSE OR DATA ERROR HANDLING
              714/724          .Digital logic testing
              714/725          ..Programmable logic array (PLA) testing


  2   714/729         (0 OR, 2 XR)
              Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                                  DETECTION/RECOVERY
              714/699          PULSE OR DATA ERROR HANDLING
              714/724          .Digital logic testing
              714/726          ..Scan path testing (e.g., level sensitive sca
n
                               design (LSSD))
              714/729          ...Plural scan paths


  2   714/742         (0 OR, 2 XR)
              Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                                  DETECTION/RECOVERY
              714/699          PULSE OR DATA ERROR HANDLING
```

```
                   09872582_CLSTITLES
       714/724        .Digital logic testing
       714/738        ..Including test pattern generator
       714/742        ...Testing specific device

2   714/8         (0 OR, 2 XR)
       Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                         DETECTION/RECOVERY
       714/100         DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

       714/1           .Reliability and availability
       714/2           ..Fault recovery
       714/3           ...By masking or reconfiguration
       714/5           ....Of memory or peripheral subsystem
       714/8           .....Isolating failed storage location (e.g.,
                           sector remapping)
```

PLUS Search Results for S/N 09872582, Searched May 19, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search
system for U.S. Patents from 1971 to the present. PLUS is a
query-by-example search system which produces a list of patents that are
most closely related linguistically to the application searched. This
search was prepared by the staff of the Scientific and Technical
Information Center, SIRA.

6667917
6067262
5956350
6367042
6651202
5920515
6560740
6304989
5987632
5909404
6425103
6505308
4918378
5006787
6300769
6505313
6640321
6373758
5675545
6065134
6249893
5862151
5982681
5425035
5577050
5258986
5761215
6185709
5748543
6085334
6408401
6691252
6718496
5968192
6044481
5471482
5936876

6018484
6185138
6151692
6167544
6510530
6249889
5825785
5668947
5724367
5784382
6341092
6388930
5640509

```
6667917 93
6067262 88
5956350 88
6367042 88
6651202 88
5920515 86
6560740 85
6304989 83
5987632 80
5909404 80
6425103 80
6505308 80
4918378 78
5006787 78
6300769 74
6505313 74
6640321 74
6373758 73
5675545 73
6065134 72
6249893 72
5862151 72
5982681 72
5425035 71
5577050 71
5258986 70
5761215 70
6185709 70
5748543 68
6085334 68
6408401 68
6691252 68
6718496 68
5968192 67
6044481 67
5471482 67
5936876 67
6018484 67
6185138 67
6151692 67
6167544 67
6510530 67
6249889 67
5825785 67
5668947 66
5724367 66
5784382 66
6341092 66
```

6388930 66
5640509 65